



National Standards Authority of Ireland

IRISH STANDARD

**I.S. EN 60749-14:2003**

ICS 31.080.01

**SEMICONDUCTOR DEVICES -  
MECHANICAL AND CLIMATIC TEST  
METHODS  
PART 14: ROBUSTNESS OF TERMINATIONS  
(LEAD INTEGRITY)  
((EC 60749-14:2003))**

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EUROPEAN STANDARD

**EN 60749-14**

NORME EUROPÉENNE

EUROPÄISCHE NORM

October 2003

ICS 31.080.01

English version

**Semiconductor devices -  
Mechanical and climatic test methods  
Part 14: Robustness of terminations (lead integrity)  
(IEC 60749-14:2003)**

Dispositifs à semiconducteurs -  
Méthodes d'essais  
mécaniques et climatiques  
Partie 14: Robustesse des sorties  
(intégrité des connexions)  
(CEI 60749-14:2003)

Halbleiterbauelemente -  
Mechanische und klimatische  
Prüfverfahren  
Teil 14: Festigkeit der  
Bauelementeanschlüsse  
(Unversehrtheit der Anschlüsse)  
(IEC 60749-14:2003)

This European Standard was approved by CENELEC on 2003-10-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

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**CENELEC**

European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**Central Secretariat: rue de Stassart 35, B - 1050 Brussels**

## Foreword

The text of document 47/1701/FDIS, future edition 1 of IEC 60749-14, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60749-14 on 2003-10-01.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2004-07-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2006-10-01

Annexes designated "normative" are part of the body of the standard.  
In this standard, annex ZA is normative.  
Annex ZA has been added by CENELEC.

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## Endorsement notice

The text of the International Standard IEC 60749-14:2003 was approved by CENELEC as a European Standard without any modification.

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## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

| <u>Publication</u> | <u>Year</u>     | <u>Title</u>  | <u>EN/HD</u> | <u>Year</u>        |
|--------------------|-----------------|---|--------------|--------------------|
| IEC 60749-8        | - <sup>1)</sup> | Semiconductor devices - Mechanical and climatic test methods<br>Part 8: Sealing | EN 60749-8   | 2003 <sup>2)</sup> |

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<sup>1)</sup> Undated reference.

<sup>2)</sup> Valid edition at date of issue.



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